

## CA3310AD

### CMOS, 10-Bit, A/D Converters with Internal Track and Hold

The Harris CA3310 is a fast, low power, 10-bit successive approximation analog-to-digital converter, with microprocessor compatible outputs. It uses only a single 3V to 6V supply and typically draws Just 3mA when operating at 5V. It can accept full rail-to-rail input signals, and features a built-in track and hold. The track and hold will follow high bandwidth input signals, as it has only a 100ns (typical) input time constant.

The ten data outputs feature full high-speed CMOS threestate bus driver capability, and are latched and held through a full conversion cycle. Separate 8 MSB and 2 LSB enables, a data ready flag, and conversion start and ready reset inputs complete the microprocessor interface.

An internal, adjustable clock is provided and is available as an output. The clock may also be driven from an external source.

#### Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All re-creations are done with the approval of the Original Component Manufacturer (OCM).

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

#### Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-35835
  - Class Q Military
  - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
  - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

*The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OCM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.*

#### FOR REFERENCE ONLY

August 1997

### Features

- CMOS Low Power (Typ).....15mW
- Single Supply Voltage .....3V to 6V
- Conversion Time .....13μs
- Built-In Track and Hold
- Rail-to-Rail Input Range
- Latched Three-state Output Drivers
- Microprocessor-Compatible Control Lines
- Internal or External Clock

### Applications

- Fast, No-Droop, Sample and Hold
- Voice Grade Digital Audio
- DSP Modems
- Remote Low Power Data Acquisition Systems
- μP Controlled Systems

### Description

The Harris CA3310 is a fast, low power, 10-bit successive approximation analog-to-digital converter, with microprocessor-compatible outputs. It uses only a single 3V to 6V supply and typically draws just 3mA when operating at 5V. It can accept full rail-to-rail input signals, and features a built-in track and hold. The track and hold will follow high bandwidth input signals, as it has only a 100ns (typical) input time constant.

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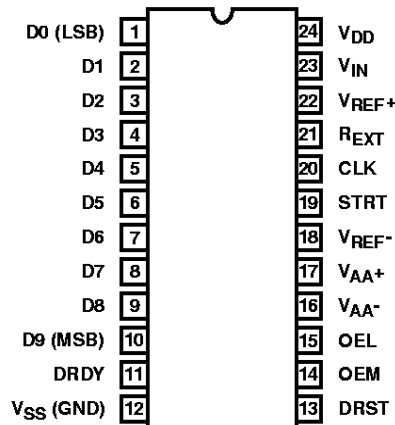
An internal, adjustable clock is provided and is available as an output. The clock may also be driven from an external source.

### Ordering Information

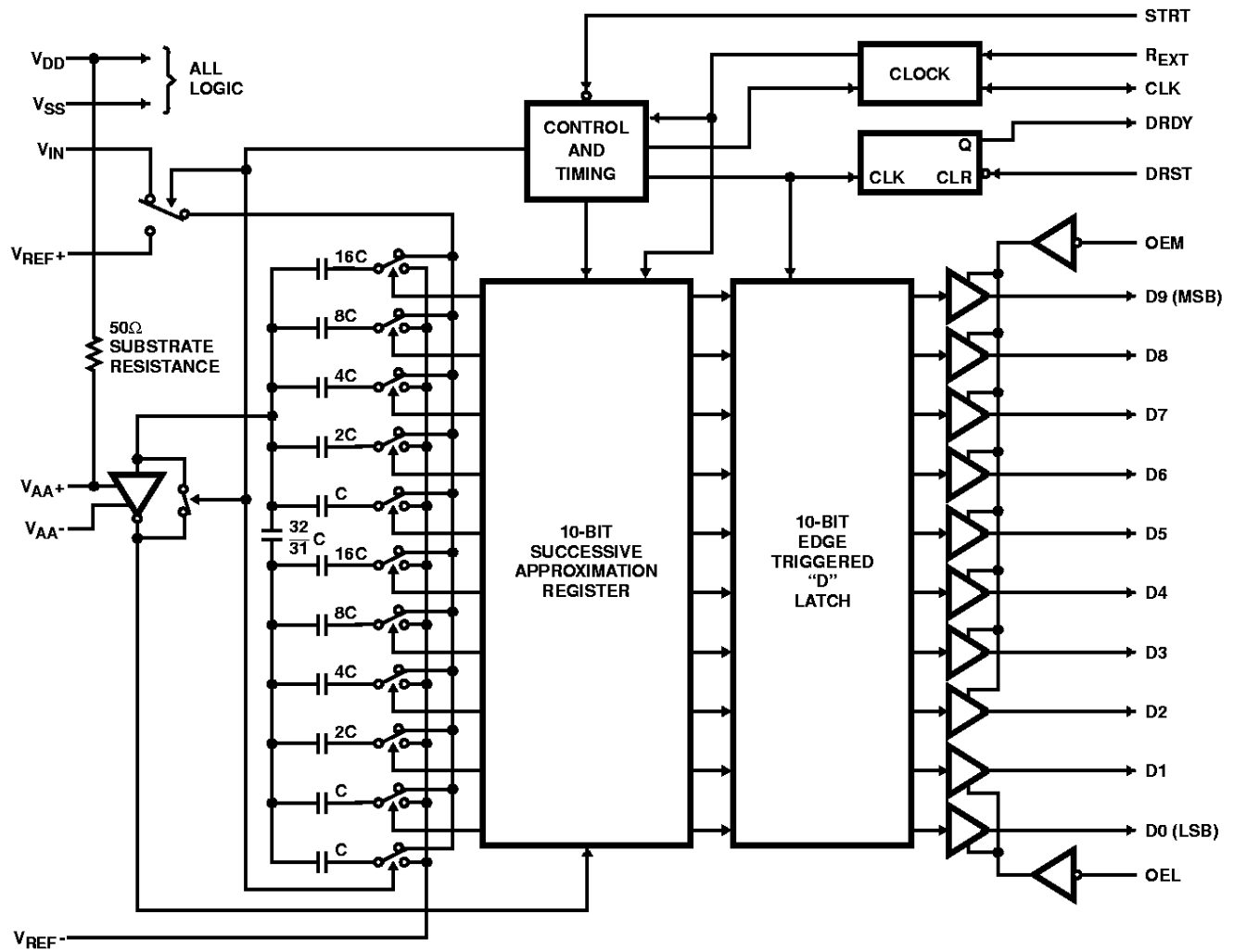
PART NUMBER	LINEARITY (INL, DNL)	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
CA3310E	±0.75 LSB	-40 to 85	24 Ld PDIP	E24.6
CA3310AE	±0.5 LSB	-40 to 85	24 Ld PDIP	E24.6
CA3310M	±0.75 LSB	-40 to 85	24 Ld SOIC	M24.3
CA3310AM	±0.5 LSB	-40 to 85	24 Ld SOIC	M24.3
CA3310D	±0.75 LSB	-55 to 125	24 Ld SBDIP	D24.6
CA3310AD	±0.5 LSB	-55 to 125	24 Ld SBDIP	D24.6

### Pinout

CA3310, CA3310A  
(PDIP, SBDIP, SOIC)  
TOP VIEW

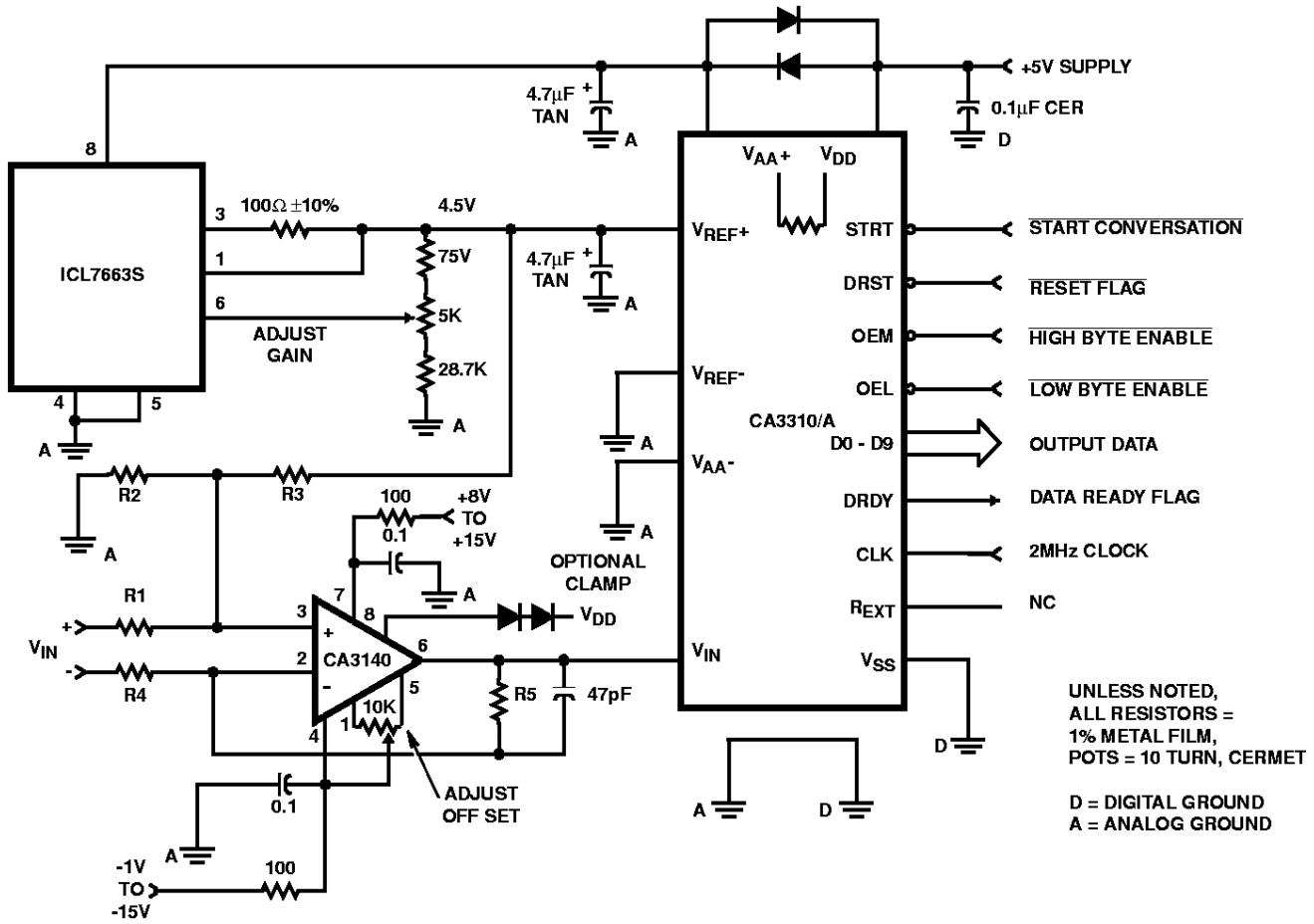


Functional Block Diagram



## CA3310, CA3310A

### Typical Application Schematics



INPUT RANGE	R1	R2	R3	R4	R5
0V TO 2.5V	4.99K	9.09K	OPEN	4.99K	9.09K
0V TO 5V	4.99K	4.53K	OPEN	4.99K	4.53K
0V TO 10V	10K	4.53K	OPEN	10K	4.53K
-2.5V TO +2.5V	4.99K	9.09K	9.09K	4.99K	4.53K
-5V TO +5V	10K	9.09K	9.09K	10K	4.53K

# CA3310, CA3310A

## Absolute Maximum Ratings

Digital Supply Voltage $V_{DD}$ . . . . .	$V_{SS} - 0.5V$ to $V_{SS} + 7V$
Analog Supply Voltage ( $V_{AA+}$ ) . . . . .	$V_{DD} \pm 0.5V$
Any Other Terminal . . . . .	$V_{SS} - 0.5V$ to $V_{DD} + 0.5V$
DC Input Current or Output (Protection Diode) Current . . . . .	$\pm 20mA$
DC Output Drain Current, per Output . . . . .	$\pm 35mA$
Total DC Supply or Ground Current . . . . .	$\pm 70mA$

## Operating Conditions

Temperature Range ( $T_A$ ) . . . . .	
Package Type D . . . . .	$-55^{\circ}C$ to $125^{\circ}C$
Package Type E, M . . . . .	$-40^{\circ}C$ to $85^{\circ}C$

## Thermal Information

Thermal Resistance (Typical, Note 1)	$\theta_{JA}$ ( $^{\circ}C/W$ )	$\theta_{JC}$ ( $^{\circ}C/W$ )
PDIP Package . . . . .	75	N/A
SBDIP Package . . . . .	70	22
SOIC Package . . . . .	75	N/A
Maximum Junction Temperature		
Plastic Packages . . . . .		$150^{\circ}C$
Hermetic Package . . . . .		$175^{\circ}C$
Maximum Storage Temperature ( $T_{STG}$ ) . . . . .		$-65^{\circ}C$ to $150^{\circ}C$
Maximum Lead Temperature (Soldering 10s) . . . . .		$300^{\circ}C$ (SOIC - Lead Tips Only)

**CAUTION:** Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

**NOTE:**

- $\theta_{JA}$  is measured with the component mounted on an evaluation PC board in free air.

**Electrical Specifications**  $T_A = 25^{\circ}C$ ,  $V_{DD} = V_{AA+} = 5V$ ,  $V_{REF+} = 4.608V$ ,  $V_{SS} = V_{AA-} = V_{REF-} = GND$ , CLK = External 1MHz, Unless Otherwise Specified

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
<b>ACCURACY</b> (See Text For Definitions)					
Resolution		10	-	-	Bits
Differential Linearity Error	CA3310	-	$\pm 0.5$	$\pm 0.75$	LSB
	CA3310A	-	$\pm 0.25$	$\pm 0.5$	LSB
Integral Linearity Error	CA3310	-	$\pm 0.5$	$\pm 0.75$	LSB
	CA3310A	-	$\pm 0.25$	$\pm 0.5$	LSB
Gain Error	CA3310	-	$\pm 0.25$	$\pm 0.5$	LSB
	CA3310A	-	-	$\pm 0.25$	LSB
Offset Error	CA3310	-	$\pm 0.25$	$\pm 0.5$	LSB
	CA3310A	-	-	$\pm 0.25$	LSB
<b>ANALOG OUTPUT</b>					
Input Resistance	In Series with Input Sample Capacitors	-	330	-	$\Omega$
Input Capacitance	During Sample State	-	300	-	pF
Input Capacitance	During Hold State	-	20	-	pF
Input Current	At $V_{IN} = V_{REF+} = 5V$	-	-	+300	$\mu A$
	At $V_{IN} = V_{REF-} = 0V$	-	-	-100	$\mu A$
Static Input Current	STRT = V+, CLK = V+ At $V_{IN} = V_{REF+} = 5V$	-	-	1	$\mu A$
	At $V_{IN} = V_{REF-} = 0V$	-	-	-1	$\mu A$
Input + Full-Scale Range	(Note 2)	$V_{REF-} + 1$	-	$V_{DD} + 0.3$	V
Input - Full-Scale Range	(Note 2)	$V_{SS} - 0.3$	-	$V_{REF+} - 1$	V
Input Bandwidth	From Input RC Time Constant	-	1.5	-	MHz
<b>DIGITAL INPUTS</b> DRST, OEL, OEM, STRT, CLK					
High-Level Input Voltage	Over $V_{DD} = 3V$ to $6V$ (Note 2)	70	-	-	% of $V_{DD}$
Low-Level Input Voltage	Over $V_{DD} = 3V$ to $6V$ (Note 2)	-	-	30	% of $V_{DD}$
Input Leakage Current	Except CLK	-	-	$\pm 1$	$\mu A$
Input Capacitance	(Note 2)	-	-	10	pF
Input Current	CLK Only (Note 2)	-	-	$\pm 400$	$\mu A$

## CA3310, CA3310A

**Electrical Specifications**  $T_A = 25^\circ\text{C}$ ,  $V_{DD} = V_{AA+} = 5\text{V}$ ,  $V_{REF+} = 4.608\text{V}$ ,  $V_{SS} = V_{AA-} = V_{REF-} = \text{GND}$ , CLK = External 1MHz, Unless Otherwise Specified **(Continued)**

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS	
<b>DIGITAL OUTPUTS</b> D0 - D9, DRDY						
High-Level Output Voltage	$I_{SOURCE} = -4\text{mA}$	4.6	-	-	V	
Low-Level Output Voltage	$I_{SINK} = 6\text{mA}$	-	-	0.4	V	
Three-State Leakage	Except DRDY	-	-	$\pm 1$	$\mu\text{A}$	
Output Capacitance	Except DRDY (Note 2)	-	-	20	pF	
<b>CLK OUTPUT</b>						
High-Level Output Voltage	$I_{SOURCE} = 100\mu\text{A}$ (Note 2)	4	-	-	V	
Low-Level Output Voltage	$I_{SINK} = 100\mu\text{A}$ (Note 2)	-	-	1	V	
<b>TIMING</b>						
Clock Frequency	Internal, CLK and $R_{EXT}$ Open	200	300	400	kHz	
	Internal, CLK Shorted to $R_{EXT}$	600	800	1000	kHz	
	External, Applied to CLK (Note 2)	(Max)	-	4	2	MHz
		(Min)	100	10	-	kHz
Clock Pulse Width, $t_{LOW}$ , $t_{HIGH}$	External, Applied to CLK: See Figure 1 (Note 2)	100	-	-	ns	
Conversion Time	Internal, CLK Shorted to $R_{EXT}$	13	-	-	$\mu\text{s}$	
Aperture Delay, $t_D$ APR	See Figure 1	-	100	-	ns	
Clock to Data Ready Delay, $t_{D1}$ DRDY	See Figure 1	-	150	-	ns	
Clock to Data Ready Delay, $t_{D2}$ DRDY	See Figure 1	-	250	-	ns	
Clock to Data Delay, $t_D$ Data	See Figure 1	-	200	-	ns	
Start Removal Time, $t_R$ STRT	See Figures 3 and 4 (Note 1)	-	-120	-	ns	
Start Setup Time, $t_{SU}$ STRT	See Figure 4	-	160	-	ns	
Start Pulse Width, $t_W$ STRT	See Figures 3 and 4	-	10	-	ns	
Start to Data Ready Delay, $t_{D3}$ DRDY	See Figures 3 and 4	-	170	-	ns	
Clock Delay from Start, $t_D$ CLK	See Figure 3	-	200	-	ns	
Ready Reset Removal Time, $t_R$ DRST	See Figure 50 (Note 1)	-	-80	-	ns	
Ready Reset Pulse Width, $t_W$ DRST	See Figure 5	-	10	-	ns	
Ready Reset to Data Ready Delay, $t_{D4}$ DRDY	See Figure 5	-	35	-	ns	
Output Enable Delay, $t_{EN}$	See Figure 2	-	40	-	ns	
Output Disable Delay, $t_{DIS}$	See Figure 2	-	50	-	ns	
<b>SUPPLIES</b>						
Supply Operating Range, $V_{DD}$ or $V_{AA}$	(Note 2)	3	-	6	V	
Supply Current, $I_{DD} + I_{AA}$	See Figures 14, 15	-	3	8	mA	
Supply Standby Current	Clock Stopped During Cycle 1	-	3.5	-	mA	
Analog Supply Rejection	At 120Hz, See Figure 13	-	25	-	mV/V	
Reference Input Current	See Figure 10	-	160	-	$\mu\text{A}$	
<b>TEMPERATURE DEPENDENCY</b>						
Offset Drift	At 0 to 1 Code Transition	-	-4	-	$\mu\text{V}/^\circ\text{C}$	
Gain Drift	At 1022 to 1023 Code Transition	-	-6	-	$\mu\text{V}/^\circ\text{C}$	
Internal Clock Speed	See Figure 7	-	-0.5	-	$\%/^\circ\text{C}$	

**NOTES:**

1. A (-) removal time means the signal can be removed after the reference signal.
2. Parameter not tested, but guaranteed by design or characterization.